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PATENT

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Applicant : Shigeki Ueda et al.  
Filed : Herewith  
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Examiner : TBD  
  
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INFORMATION DISCLOSURE STATEMENT

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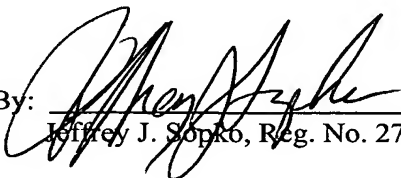
Sir/Madam:

In accordance with Rule 56, applicants are aware of the publications listed in the International Search Report (ISR, copy enclosed) and in the enclosed copy of Patent Office Form 1449. Copies of the publications cited in the International Search Report are not enclosed as they were previously forwarded by the International Bureau, however, copies of the publications cited in the specification are enclosed.

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Respectfully submitted,

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		FILING DATE: <b>Herewith</b>	GROUP ART UNIT: <b>TBD</b>

## U.S. PATENT DOCUMENTS

Examiner Initial		Document No.	Date	Name	Class	Subclass	Filing Date If Appropriate
	A						
	B						
	C						
	D						
	E						
	F						

## FOREIGN PATENT DOCUMENTS

		Document No.	Date	Country	Class	Subclass	Translation
	G	7-88089	04/1995	JAPAN			Cited in Specification-English Abstract
	H	8-282358	10/1996	JAPAN			Cited in Specification-English Abstract
	I	10-14718	01/1998	JAPAN			Cited on ISR
	J	10-14888	01/1998	JAPAN			Cited on ISR
	K	10-229973	09/1998	JAPAN			Cited in Specification-English Abstract
	L	2830661	09/1998	JAPAN			Cited on ISR
	M	3001378	11/1999	JAPAN			Cited on ISR
	N	2000-214004	08/2000	JAPAN			Cited on ISR
	O	2003-52765	03/2003	JAPAN			Cited in Specification-English Abstract
	P	2004-154242	06/2004	JAPAN			Cited on ISR

## OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

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